XRF Plating Measurement Instruments

G

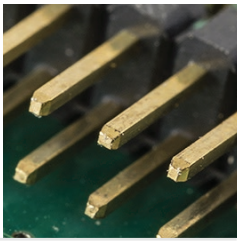
G Series' two most distinctive features are precision video imaging, and 'bottom-up' measurement using a motorized Z-axis with laser-based auto-focus. *The latter is a feature unique to Bowman.* An available manual X-Y stage with 1.5 X 1.5' travel facilitates easy positioning of parts.

B

B Series is the most basic top-down measurement configuration. The sample stage is a fixed base; operators place parts in the chamber and use the video image to align the desired location within the crosshairs on the screen. The sample chamber is the same as the P Series, with the slotted configuration, but without the programmable X-Y sample stage.

P

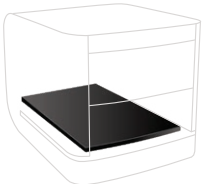
P Series efficiently measures the widest range of sample sizes, shapes, and quantities. It is equipped with a high precision programmable X-Y stage that offers several convenience factors over a fixed stage. Operators use the mouse and software interface to move easily to desired measurement locations.



L

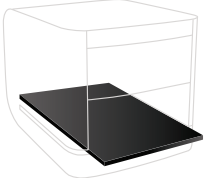
L Series is Bowman's most versatile instrument, combining the features of the P Series with a larger sample chamber and greater X-Y stage travel. For samples larger than ~12 inches (300 mm) in any direction, the L Series is the industry's best option. The large sample stage and travel accommodates large parts, and large fixtures.

Bowman has a Chamber Size for Every Application

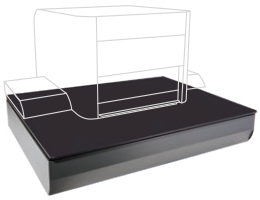


Standard
Fixed Base

Extended
Programmable
XY Base



Motorized
Programmable
XY Base



Maximum
Travel Extended
XY Base

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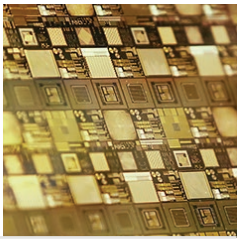
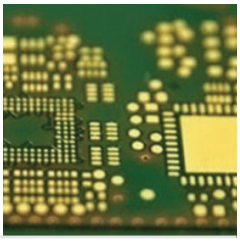
O Series was engineered for features >100 µm and sample sizes up to 400x400 mm. Available in slotted or closed chamber design. Closed chamber accommodates taller samples or fixtures with X-Y sample coverage to 250 mm. If features are <100 µm, M or W Series systems are the best options.

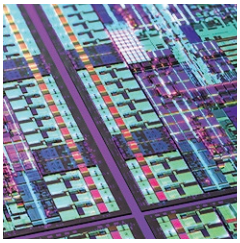


M Series was engineered for features <100 µm to 20 µm and flat samples such as wafers or PCBs. Sample size can be up to 400x40 mm for full X-Y stage coverage. If chuck/fixture is required for mounting sample, fixture height up to 13 mm can be accommodated. If sample size is >400x400 mm or if the chuck or fixture is >13 mm tall, W Series is the preferred option.



W Series was engineered for features <100 µm to 20 µm, and creates stage clearance for fixtures up to 100 mm tall. Sample size can be up to 300x400 mm for ll X-Y stage coverage. Perfect for wafers with chucks. W Series provides performance and versatility with smallest spot sizes; highest precision stage, and compatibility with all wafer sizes.

A Series was engineered for features <100 µm down to 20 µm, and creates stage clearance for fixtures up to 100 mm tall. Sample size can be up to 600x600 mm with full X-Y stage coverage. The best all-around performance and versatility with the smallest spot size, highest precision stage, and largest sample capabilities.



Every XRF in the Bowman Benchtop Suite has a Silicon Drift Detector (SDD) for lowest baseline noise, highest counts detection, highest resolution and best detection limits

MADE IN USA

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